

File 347:JAPIO Oct 1976-2003/Aug(Updated 031202)

(c) 2003 JPO & JAPIO

File 350:Derwent WPIX 1963-2003/UD,UM &UP=200378

(c) 2003 Thomson Derwent

Set	Items	Description
S1	59882	(ERROR? ? OR PARITY) (3N) (CHECK??? OR EXAM? OR TEST??? OR D- ETECT? OR ANALYZ? OR ANALYS?)
S2	94249	(SECOND? OR 2ND OR TWO OR SEPARAT? OR DIFFERENT OR ANOTHER OR OTHER) (5W) (MEMORY OR MEMORIES OR RAM OR STORE OR STORES OR STORAGE)
S3	107531	MULTIPLEX?
S4	64	S1 AND S2 AND S3
S5	1010	S2(20N)S3
S6	30	S4 AND S5
S7	30	IDPAT (sorted in duplicate/non-duplicate order)
S8	3397	DUAL?(5W) (MEMORY OR MEMORIES OR RAM OR STORE OR STORES OR - STORAGE)
S9	0	S8(20N)S3 AND S1

7/19/3 (Item 3 from file: 350)
DIALOG(R) File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

011115634 **Image available**
WPI Acc No: 1997-093559/199709
XRPX Acc No: N97-077438

SOH termination circuit for SOH wireless transmission system - has RSOH multiplexer which multiplexes signals input from MSOH multiplexer and outputs multiplexed STM-N signal

Patent Assignee: NEC CORP (NIDE)
Number of Countries: 001 Number of Patents: 001
Patent Family:
Patent No Kind Date Applicat No Kind Date Week
JP 8331088 A 19961213 JP 95152507 A 19950526 199709 B

Priority Applications (No Type Date): JP 95152507 A 19950526

Patent Details:
Patent No Kind Lan Pg Main IPC Filing Notes
JP 8331088 A 5 H04J-003/08

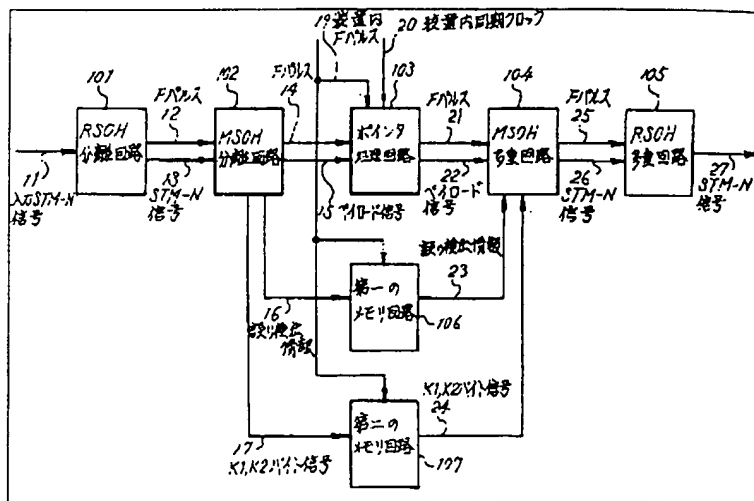
Abstract (Basic): JP 8331088 A

The circuit consists of a RSOH separation unit (101) to which a composite STM-N signal (11) is input. This unit establishes frame synchronization and separates input signal as descramble signal (12) and STM-N signal (13). Then, an MSOH separation unit (102) separates input signal further as MSOH signal (16) and is output to a first memory unit (106) and K1 and two bytes of Ks signal for **error detection** is given to a **second memory** unit (107). F pulse (19) from an external device is also fed to the first and **second memory** units and to a pointer processing unit (103). The MSOH separation unit outputs frame pulse (14) and a pay load signal (15) to the pointer processing unit in synchronization with clock signal (20) from an external device. The output signals (23,24) of the first and **second memory** units is fed to an MSOH **multiplexer** (104).

The output frame pulse (21) and processed pay load signal (22) from the pointer processing unit is also fed to the MSOH **multiplexer**. When the bit interleave parity signal output from **second memory** unit differs from the signals K1 and two bytes of Ks for **error detection**, the corresponding **parity** bit of the pay load signal is inverted. The **multiplexed** outputs (25,26) from the MSOH **multiplexer** is fed to an RSOH **multiplexer** (105) which **multiplexes** RSOH and scramble signals and outputs **multiplexed** STM-N signal.

ADVANTAGE - Enables ring protection between STM-N **multiplexes** in SDH wireless transmission system.

Dwg.1/2



Title Terms: TERMINATE; CIRCUIT; WIRELESS; TRANSMISSION; SYSTEM; **MULTIPLEX**
; **MULTIPLEX** ; SIGNAL; INPUT; **MULTIPLEX** ; OUTPUT; **MULTIPLEX** ; STM; N;

SIGNAL

Derwent Class: W02

International Patent Class (Main): H04J-003/08

International Patent Class (Additional): H04J-003/00

File Segment: EPI

Manual Codes (EPI/S-X): W02-K02; W02-K02B3

7/19/6 (Item 6 from file: 350)

DIALOG(R) File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

013009867 **Image available**

WPI Acc No: 2000-181719/200016

XRFX Acc No: N00-134136

Data access method for values stored in cache of computer, in which dual associative-cache directories are configured to allow simultaneous read operation using two buses with multiplexers

Patent Assignee: INT BUSINESS MACHINES CORP (IBMC)

Inventor: ARIMILLI R K; DODSON J S; LEWIS J D; SKERGAN T M

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 6023746	A	20000208	US 97839558	A	19970414	200016 B

Priority Applications (No Type Date): US 97839558 A 19970414

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
US 6023746	A	12	G06F-012/00	

Abstract (Basic): US 6023746 A

NOVELTY - Dual associative-cache directories allow simultaneous read operations using **two** buses with **multiplexers**, address tags, **memory** block control signals, single clock cycle operation and error correction.

DETAILED DESCRIPTION - The method involves accessing values stored in a cache used by a processor, such that **two** read operations may occur simultaneously. **Memory** blocks from a memory device are loaded into respective cache lines of the cache memory, and address tags associated with the memory blocks are written into two redundant cache directories of the cache. Memory blocks can then be read from the cache using either of the two cache directories. INDEPENDENT CLAIMS are included for; a computer system with cache memory access mechanism for accessing values stored in a cache.

USE - Dual associative-cache directories for simultaneous read operation, in which read operations may occur simultaneously.

ADVANTAGE - Provide cache that efficiently uses all available cache lines without excess logic circuits in the critical path. Improved handling of defects, including defect avoidance and error correction. Provides cache having faster read access.

DESCRIPTION OF DRAWING(S) - The drawing shows a high-level schematic diagram of a set associative cache according to the invention, with parity error control and dynamic repair mask.

Set associative cache (70)

Cache directory (72)

LRU array (74)

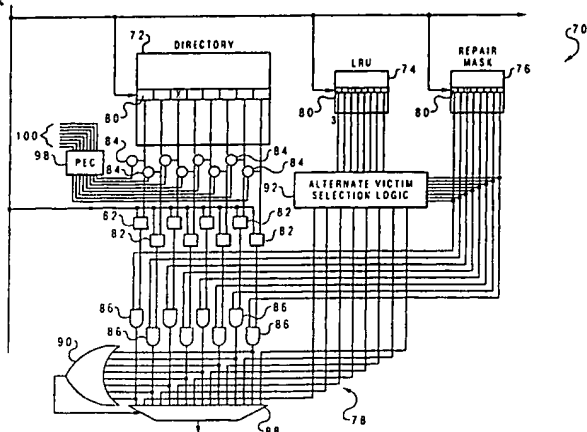
Repair mask (76)

Control logic (78)

Comparators (82)

Parity checkers (84)

pp; 12 DwgNo 3/4



Title Terms: DATA; ACCESS; METHOD; VALUE; STORAGE; CACHE; COMPUTER; DUAL;
 ASSOCIATE; CACHE; DIRECTORY; CONFIGURATION; ALLOW; SIMULTANEOUS; READ;
 OPERATE; TWO; BUS; **MULTIPLEX**
 Derwent Class: T01
 International Patent Class (Main): G06F-012/00
 File Segment: EPI
 Manual Codes (EPI/S-X): T01-H03A; T01-M05

7/19/7 (Item 7 from file: 350)
 DIALOG(R)File 350:Derwent WPIX
 (c) 2003 Thomson Derwent. All rts. reserv.

012932609
 WPI Acc No: 2000-104456/200009
 XRPX Acc No: N00-080172

Device for phase synchronization

Patent Assignee: PENZA TECHN INST (PETE-R)
 Inventor: CHULKOV V A
 Number of Countries: 001 Number of Patents: 001
 Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
RU 2119717	C1	19980927	RU 97106276	A	19970415	200009 B

Priority Applications (No Type Date): RU 97106276 A 19970415

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
RU 2119717	C1		H03L-007/00	

Abstract (Basic): RU 2119717 C1

NOVELTY - Device provides synchronization for reception of digital information and is based on direct automatic phase tuning without alternation of heterodyne frequency. Device has multiple-phase reference oscillator, which outputs are connected to information inputs of **multiplexer**. Goal of invention is achieved by introduced adder-subtractor, adder, bit-by-bit shift register, **two memory** registers. One **memory** register has encoder and is reads phase of input signals. **Second memory** register serves as digital filter together with adder-subtractor and bit-by-bit shift register. Current phase **error** is **detected** by adder operating in complementary code.

USE - Communication.

ADVANTAGE - Increased bandwidth of synchronization, increased speed of initiating synchronization, increased dynamic precision of synchronization. 1 dwge

pp; 0 DwgNo 0/0

Title Terms: DEVICE; PHASE
 Derwent Class: U22; U23; W01
 International Patent Class (Main): H03L-007/00
 International Patent Class (Additional): H04L-007/033
 File Segment: EPI
 Manual Codes (EPI/S-X): U22-H; U23-D; W01-A04B1

7/19/8 (Item 8 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

012902172 **Image available**
WPI Acc No: 2000-074008/200007
XRPX Acc No: N00-057953

Sampling flip-flop for testing digital logic at end of production line

Patent Assignee: NAT SEMICONDUCTOR CORP (NASC)

Inventor: QURESHI F U R

Number of Countries: 003 Number of Patents: 005

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week	
DE 19927094	A1	19991230	DE 1027094	A	19990615	200007	B
KR 2000005741	A	20000125	KR 9919563	A	19990529	200063	
US 6182256	B1	20010130	US 9898236	A	19980616	200108	
DE 19927094	C2	20020221	DE 1027094	A	19990615	200213	
KR 327058	B	20020313	KR 9919563	A	19990529	200263	

Priority Applications (No Type Date): US 9898236 A 19980616

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
DE 19927094	A1		20	H03K-005/15	
KR 2000005741	A			H03K-019/00	
US 6182256	B1			G01R-031/28	
DE 19927094	C2			H03K-005/15	
KR 327058	B			H03K-019/00	Previous Publ. patent KR 2000005741

Abstract (Basic): DE 19927094 A1

NOVELTY - The device has **two** temporary memories (918,920), each with an input and output, and three **multiplexers**. The first **multiplexer** (930) has a serial input, a parallel input, a selection input and an output connected to the first memory's input. The second **multiplexer** (940) has a serial input connected to that of the first **multiplexer**, a flop input connected to the output of the first memory, a selection input connected to that of the first **multiplexer** and an output connected to the input of the **second memory**. The third **multiplexer** (950) has inputs connected to the memory outputs, a control input and an output.

DETAILED DESCRIPTION - An INDEPENDENT CLAIM is also included for a circuit with a chain of sampling flip-flops.

USE - For testing digital logic at the end of a production line.

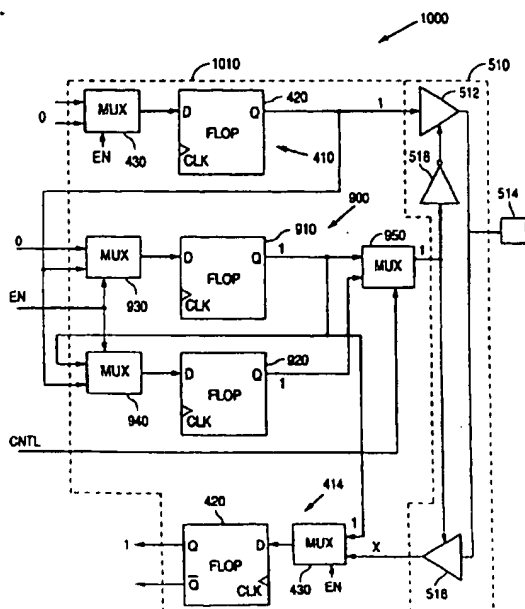
ADVANTAGE - **Test errors** caused by bi-directional connections can be prevented.

DESCRIPTION OF DRAWING(S) - The drawing shows a schematic block diagram of a sampling flip-flop

Temporary memories (918,920)

Multiplexers (930,940,950)

pp; 20 DwgNo 1/11



Title Terms: SAMPLE; FLIP; TEST; DIGITAL; LOGIC; END; PRODUCE; LINE
 Derwent Class: S01; U21; U22
 International Patent Class (Main): G01R-031/28; H03K-005/15; H03K-019/00
 International Patent Class (Additional): G01R-031/3183
 File Segment: EPI
 Manual Codes (EPI/S-X): S01-G01A5; U21-C03D1; U22-A04C; U22-D06

7/19/9 (Item 9 from file: 350)
 DIALOG(R) File 350:Derwent WPIX
 (c) 2003 Thomson Derwent. All rts. reserv.

012887956 **Image available**
 WPI Acc No: 2000-059790/200005
 XRPX Acc No: N00-047015

Frequency modulation multiplex broadcast receiver for vehicle-mounted navigation system - has frame synchronization detection unit that detects timing by which frames of the secondary information are synchronized, and memory into which initial and secondary information are stored

Patent Assignee: ALPINE KK (ALPN)
 Number of Countries: 001 Number of Patents: 001
 Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
JP 11317679	A	19991116	JP 98121964	A	19980501	200005 B

Priority Applications (No Type Date): JP 98121964 A 19980501

Patent Details:
 Patent No Kind Lan Pg Main IPC Filing Notes
 JP 11317679 A 9 H04B-001/16

Abstract (Basic): JP 11317679 A

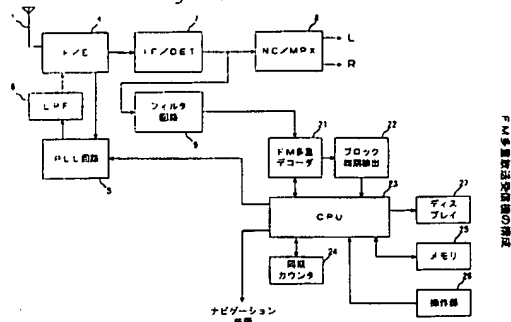
NOVELTY - The synchronous block detector circuit detects the synchronization of the blocks contained in the secondary information demodulated by the FM multiplex decoder. A frame synchronization detection unit detects the timing by which the frames of the secondary information are synchronized, while the initial and secondary information are stored into a memory (25). DETAILED DESCRIPTION - A CPU (23) controls the frequency by which FM multiplex broadcasts are received by a broadcast receiver. An FM multiplex decoder (21) has a correction processor that corrects the errors of a synchronous block detector circuit (22) used in detecting synchronized blocks and the frame-synchronizing operations of a demodulator based on the initial information output from the broadcast receiver.

USE - For vehicle-mounted navigation system.

ADVANTAGE - Block and frame synchronization does not have to be

detected again even if receiving stations situated between FM **multiplex** broadcast stations are switched. Errors in initial information are reliably recovered using cyclic redundancy **check** , **parity** bits, or **parity** blocks. Reduces operating load of CPU. DESCRIPTION OF DRAWING(S) - The figure shows the block diagram of the FM **multiplex** broadcast receiver. (21) FM **multiplex** decoder; (22) Synchronous block detector circuit; (23) CPU; (25) Memory.

Dwg.1/6



Title Terms: FREQUENCY; MODULATE; **MULTIPLEX** ; BROADCAST; RECEIVE; VEHICLE; MOUNT; NAVIGATION; SYSTEM; FRAME; DETECT; UNIT; DETECT; TIME; FRAME; SECONDARY; INFORMATION; MEMORY; INITIAL; SECONDARY; INFORMATION; STORAGE
Derwent Class: S02; T07; W02; W06
International Patent Class (Main): H04B-001/16
International Patent Class (Additional): G01C-021/00; G01S-005/14; G08G-001/09; G08G-001/0969
File Segment: EPI
Manual Codes (EPI/S-X): S02-B08; T07-B; W02-G03; W06-A03

7/19/10 (Item 10 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

012588580 **Image available**
WPI Acc No: 1999-394687/199933
Related WPI Acc No: 1998-144927
XRPX Acc No: N99-295009

Signal path error testing method for pumped voltage gates in field programmable gate array

Patent Assignee: XILINX INC (XILI-N)
Inventor: ERICKSON C R; MEHROTRA A
Number of Countries: 001 Number of Patents: 001
Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 5920201	A	19990706	US 96588160	A	19960117	199933 B
			US 97935567	A	19970923	

Priority Applications (No Type Date): US 96588160 A 19960117; US 97935567 A 19970923

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
US 5920201	A		9	G01R-027/22	Div ex application US 96588160 Div ex patent US 5717340

Abstract (Basic): US 5920201 A

NOVELTY - A test signal and inverted test signal is supplied to the control transistors (504,505) respectively provided in the lines (502,503). Based on the signals, the memory cell (509) controls the pass gate to signal to line (513). The output signal is monitored on line to determine error in signal path.

DETAILED DESCRIPTION - The memory outputs signal at a threshold voltage greater than the test signal voltage. Two inverters (506,507) are coupled in between the two lines. A configuration bit is stored in the **secondary memory** cell. Based on this bit the electrical signal is **multiplexed** between two lines. An INDEPENDENT CLAIM is also included for test circuit for testing a signal path.

USE - To determine the error in signal path for pumped voltage gates.

ADVANTAGE - As three transistors and three test signals are used, error detection in signal path is faster.

DESCRIPTION OF DRAWING(S) - The figure depicts the signal path error testing method from two local lines through a pass gate on to another line.

Lines (502,503)

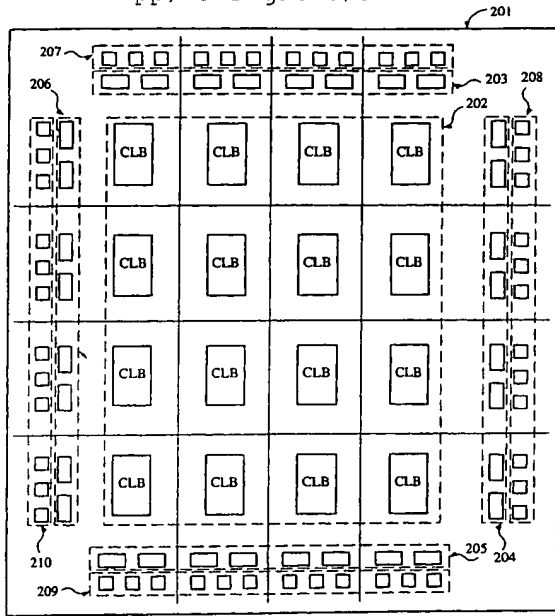
Inverter (506,507)

Memory cell (501,509)

Pass gate (508)

Output line (513)

pp; 9 DwgNo 5/5



Title Terms: SIGNAL; PATH; ERROR; TEST; METHOD; PUMP; VOLTAGE; GATE; FIELD; PROGRAM; GATE; ARRAY

Derwent Class: S01; U11; U13

International Patent Class (Main): G01R-027/22

File Segment: EPI

Manual Codes (EPI/S-X): S01-G01A1; S01-G01A5; U11-F01C3; U13-C04D

7/19/11 (Item 11 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

011200801 **Image available**

WPI Acc No: 1997-178726/199716

XRPX Acc No: N97-147383

Data error detection and correction apparatus for shared SRAM - includes two memories divided into upper and lower regions which store primary and backup information which are coupled to multiplexer and select logic which selects correct data

Patent Assignee: HONEYWELL INC (HONE); LORDI A L (LORD-I)

Inventor: LORDI A L

Number of Countries: 019 Number of Patents: 007

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 5611042	A	19970311	US 95541989	A	19951010	199716 B
WO 9714109	A2	19970417	WO 96US16037	A	19961007	199721
WO 9714109	A3	19970605	WO 96US16037	A	19961007	199737
EP 862761	A2	19980909	EP 96937661	A	19961007	199840
			WO 96US16037	A	19961007	
EP 862761	B1	19991222	EP 96937661	A	19961007	200004
			WO 96US16037	A	19961007	
JP 11513823	W	19991124	WO 96US16037	A	19961007	200006

DE 69605820 E 20000127 JP 97515115 A 19961007
 DE 605820 A 19961007 200012
 EP 96937661 A 19961007
 WO 96US16037 A 19961007

Priority Applications (No Type Date): US 95541989 A 19951010

Cited Patents: 1.Jnl.Ref; US 4245344; No-SR.Pub

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
US 5611042	A		11	G01R-031/28	
EP 862761	B1	E		G06F-011/16	Based on patent WO 9714109
Designated States (Regional): DE FR GB					
JP 11513823	W		23	G06F-012/16	Based on patent WO 9714109
DE 69605820	E			G06F-011/16	Based on patent EP 862761
Based on patent WO 9714109					
WO 9714109	A2	E	19	G06K-000/00	
Designated States (National): JP					
Designated States (Regional): AT BE CH DE DK ES FI FR GB GR IE IT LU MC					
NL PT SE					
EP 862761	A2	E		G06F-011/16	Based on patent WO 9714109
Designated States (Regional): DE FR GB					
WO 9714109	A3			G01R-031/28	

Abstract (Basic): US 5611042 A

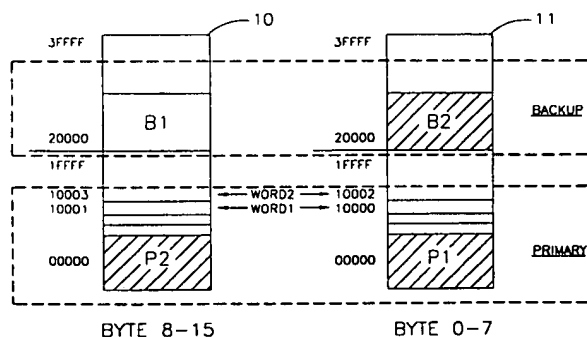
The memory information error correction apparatus includes **two memories** which are divided such that a lower memory stores primary information and an upper memory stores backup information. The upper memory addressable locations of the first memory correspond to relative addressable locations of the lower addressable memory locations of the **second memory**. A processor commands a simultaneous read of the primary information and the corresponding backup information. Memory select logic generates address information to cause the lower memories of the first memory and a corresponding relative address of the **second memory** to be read.

The primary information and the backup information is coupled to the input ports of a **multiplexer**. Select logic determines whether data in the **two memories** contains the primary or the backup information and generates a select signal to select the set of input ports containing the primary data when no error is indicated in the primary copy. The other ports are selected when an error is indicated in the primary copy and no error is indicated in the backup copy.

USE/ADVANTAGE - Error correction is performed without requiring additional time. For static random access memory.

Dwg.5/7
 SRAM 1

SRAM 2



Title Terms: DATA; ERROR; DETECT; CORRECT; APPARATUS; SHARE; SRAM; TWO; MEMORY; DIVIDE; UPPER; LOWER; REGION; STORAGE; PRIMARY; INFORMATION; COUPLE; **MULTIPLEX**; SELECT; LOGIC; SELECT; CORRECT; DATA

Derwent Class: S01; T01; U13; U14

International Patent Class (Main): G01R-031/28; G06F-011/16; G06F-012/16; G06K-000/00

International Patent Class (Additional): G06F-011/00; G11C-029/00

File Segment: EPI

Manual Codes (EPI/S-X): S01-G01; T01-G03; T01-H01B; U13-C04B1B; U14-D02

7/19/12 (Item 12 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

010468268

WPI Acc No: 1995-369587/199548

Multiplexing computer system for error detection - compares data
read out from one memory with inverted data read out from second
memory and judges disagreement in multiplexing system

Patent Assignee: TOSHIBA KK (TOKE)

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
JP 7244612	A	19950919	JP 9433574	A	19940303	199548 B

Priority Applications (No Type Date): JP 9433574 A 19940303

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
JP 7244612	A	10	G06F-012/16	

Abstract (Basic): JP 7244612 A

The **multiplexing** computer system synchronises functions of n number of elements. Each element has a calculating processing device and a memory which stores data of N bit width. The data transfer between the first calculating processing device (11-1) and the first memory (15-1) is done by first driver (18-1) through a first and second bus (17-1,12-1). Similarly the data transfer between second calculating processing device (11-2) and memory (15-2) is done by a second bus driver (18-2) through a third and fourth bus (17-2,12-2).

The first bus driver transmits the data on the first bus to the second bus which carries data to the first processing device without changing the data. The second bus driver does level inversion of the data on the third bus and then transmits the level inverted data to the fourth which carries it to the second processing device. A comparison device (B) compares the data placed on the second and fourth bus and judges the abnormality in the **multiplexing** system.

ADVANTAGE - Detects abnormality perfectly.

Dwg.1/2

Title Terms: **MULTIPLEX** ; COMPUTER; SYSTEM; ERROR; DETECT; COMPARE; DATA;
READ; ONE; MEMORY; INVERT; DATA; READ; SECOND; MEMORY; JUDGEMENT;
MULTIPLEX ; SYSTEM

Derwent Class: T01

International Patent Class (Main): G06F-012/16

International Patent Class (Additional): G06F-011/16; G06F-011/18

File Segment: EPI

Manual Codes (EPI/S-X): T01-G01A; T01-G03

7/19/13 (Item 13 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

010089948 **Image available**

WPI Acc No: 1994-357661/199444

XRPX Acc No: N94-280308

Fibre optic distributed data interface network test adaptor error
injection circuit - injects errors into FDDI network to provide
verification of operation of FDDI interface which can operate as network
node with MAC identity

Patent Assignee: INT BUSINESS MACHINES CORP (IBMC)

Inventor: ECKENRODE T; STAUFFER D R; STEMPSKI R

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 5363379	A	19941108	US 92876835	A	19920430	199444 B

Priority Applications (No Type Date): US 92876835 A 19920430

Patent Details:

Patent No Kind Lan Pg Main IPC Filing Notes
US 5363379 A 6 G06F-011/00

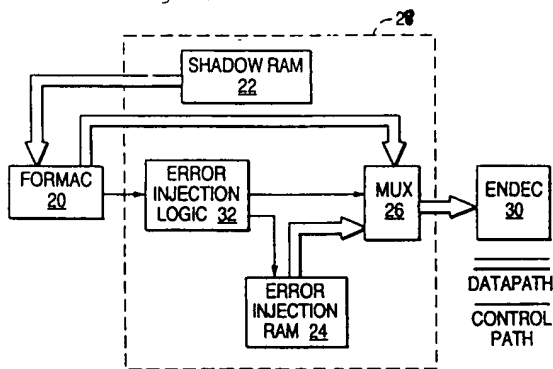
Abstract (Basic): US 5363379 A

The appts for injecting errors into a FDDI token ring network uses an error injection scheme which operates by fooling a FORMAC into thinking it sent a real frame of data, using two RAM buffers. The RAM buffer normally accessed by the RBC/DPC becomes a SHADOW RAM during error injection operation. A dummy frame is loaded into the shadow RAM in order to fool the FORMAC. The data is just like the data that would be used if sending a normal frame, with the restriction that it must be shorter than the error injection data.

The other buffer, the error injection RAM, contains the error injection frame. The error injection data is sent out to the media by switching a multiplexer. When the FORMAC is done transmitting the data, the multiplexer is switched back to the normal mode. Thus, the FORMAC is unaware of what happened and the token ring remains operational.

USE/ADVANTAGE - Injecting data frames containing errors onto fibre optic distributed data interface (FDDI) token ring network.

Dwg.1/2



Title Terms: FIBRE; OPTICAL; DISTRIBUTE; DATA; INTERFACE; NETWORK; TEST;
ADAPT; ERROR; INJECTION; CIRCUIT; INJECTION; ERROR; FDDI; NETWORK;
VERIFICATION; OPERATE; FDDI; INTERFACE; CAN; OPERATE; NETWORK; NODE; MAC;
IDENTIFY

Derwent Class: T01; W01

International Patent Class (Main): G06F-011/00

File Segment: EPI

Manual Codes (EPI/S-X): T01-G07; W01-A03A3; W01-A06A; W01-A06B2; W01-A06C1;
W01-A06D

7/19/14 (Item 14 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

010064899 **Image available**

WPI Acc No: 1994-332610/199441

XRPX Acc No: N94-261151

Reading data bits from memory for testing purposes - receiving check bits
and multi-bit word from computer memory and generating syndrome based on
detected data errors

Patent Assignee: DIGITAL EQUIP CORP (DIGI)

Inventor: GOODWIN P M; SMELSER D W; TATOSIAN D A

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 5357529	A	19941018	US 92872977	A	19920424	199441 B

Priority Applications (No Type Date): US 92872977 A 19920424

Patent Details:

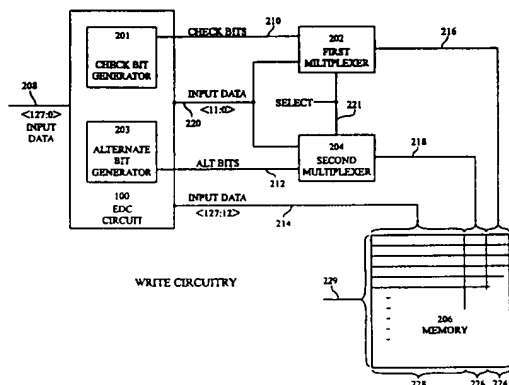
Abstract (Basic): US 5357529 A

The method involves using **error detection** and correction (EDC) circuitry, **multiplexers**, and a memory with first storage bits, **second storage** bits, and third **storage** bits. In writing data to the memory, a multi-bit data word having a first group of data bits and a second group of data bits is first received from a CPU bus. The first group of bits is written to the first storage bits. In a 'normal' mode, the second group of bits is written to the **second storage** bits. A set of check bits are calculated by the EDC circuit and written to the third storage bits. In the 'swap' mode, the second group of data bits is stored in the third storage bits.

'Alternate' bits are calculated by the EDC circuit, and written to the **second storage** bits. In **memory** reads, contents of all of the storage bits are received from the memory and directed to the **error detecting** circuit. The contents of the first storage bits are directed to error correction circuit. In the normal mode, the contents of the **second storage** bits are directed to the error correction circuit; this data is corrected if necessary, and placed on the CPU bus. In the swap mode, the contents of the third storage bits are supplied to the error correcting circuit and, along with the contents of the first storage bits, placed on the CPU bus without error correction.

ADVANTAGE - Tests computer memory check bits without introducing delay into read operations.

Dwg.2/3



Title Terms: READ; DATA; BIT; MEMORY; TEST; PURPOSE; RECEIVE; CHECK; BIT;
MULTI; BIT; WORD; COMPUTER; MEMORY; GENERATE; SYNDROME; BASED; DETECT;
DATA; ERROR

Index Terms/Additional Words: ERROR; DETECTION; AND; CORRECTION; EDC

Derwent Class: T01; U14; U21

International Patent Class (Main): H03M-013/00

File Segment: EPI

Manual Codes (EPI/S-X): T01-G01A; U14-D02; U21-A06

7/19/15 (Item 15 from file: 350)

DIALOG(R) File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

009031269 **Image available**

WPI Acc No: 1992-158629/199219

XRPX Acc No: N92-117950

Majority signals selector - processes most and least significant digit
places of code data separately with majority parity testing

Patent Assignee: MOSC VOSKHOD TOOLS (MOVO-R)

Inventor: TIMONKIN G N; TKACHENKO S N; TKACHENKO V A

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
SU 1656539	A	19910615	SU 4704244	A	19890614	199219 B

Priority Applications (No Type Date): SU 4704244 A 19890614

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
SU 1656539	A		7		

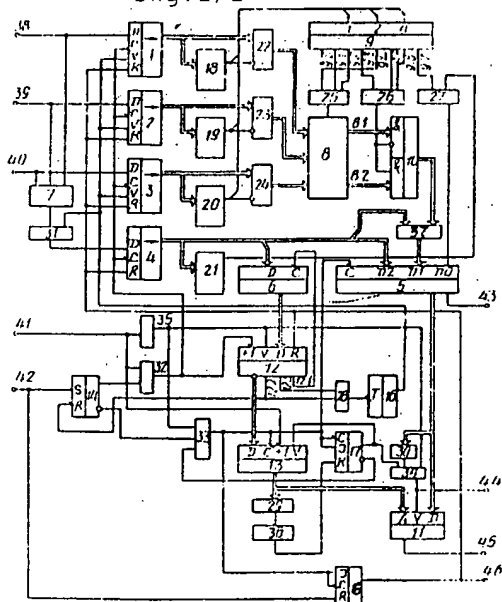
Abstract (Basic): SU 1656539 A

Appts. comprises right-shift registers (1-4), storage registers (5,6), majority element (7), ave. value calculator (8), decoder (9), commutator (10), **multiplexer** (11), counters (12,13), triggers (14-17), mod-2 adders (18-21), AND-gates (22-24), OR-gates (25-30), AND-gates (31-34), delay element (25), univibrator (36), OR-gates (37) and inputs and outputs (38-46).

When register (4) has received all K most significant digits of the data contg. data on the length of the whole piece, a pulse appears on the output of counter (12) at the instant that the synchronising pulse shifted by delay element (35) acts on the counter input. When the counter (12) value becomes equal to the length of the first part of the data, it forms a single pulse which passes via OR-gate (28) to flip trigger (16). This in turn closes AND-gate (31) and opens registers (1-3) to receive data from inputs (38-40). Then the second part of the data from both channels is entered in registers (1-3) and register (4) continues to shift data right with zeroes entered in the digit places freed left.

USE/ADVANTAGE - Appts. relates to automation and computing and may be used in high accuracy standby control systems esp. in service and measuring data processing and transmission systems. Accuracy is increased by the introduction of four right-shift registers, **two storage** registers, ave. value calculator, decoder, commutator, **multiplexer**, two counters, three triggers, four mod-2 adders, three AND-gates, four OR-gates, two AND-gates, block of OR-gates, delay element and univibrator. Bul. 22/15.6.91

Dwg. 1/1



Title Terms: MAJORITY; SIGNAL; SELECT; PROCESS; SIGNIFICANT; DIGITAL; PLACE ; CODE; DATA; SEPARATE; MAJORITY; PARITY; TEST

Derwent Class: T01

International Patent Class (Additional): G06F-011/18; H05K-010/00

File Segment: EPI

Manual Codes (EPI/S-X): T01-G01A1; T01-G03

008813901 **Image available**

WPI Acc No: 1991-317914/199143

XRPX Acc No: N91-243634

Semiconductor memory having error correction circuit - has multiplexers on outputs of memory blocks holding information and test bits, and parity test circuits responding to multiplexers

Patent Assignee: HITACHI LTD (HITA)

Inventor: AOKI M; HORIGUCHI M; ITOH K

Number of Countries: 002 Number of Patents: 002

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
US 5056095	A	19911008	US 89296135	A	19890112	199143 B
KR 9300897	B1	19930211	KR 89139	A	19890107	199417

Priority Applications (No Type Date): JP 883865 A 19880113

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
KR 9300897	B1		G11C-011/34	

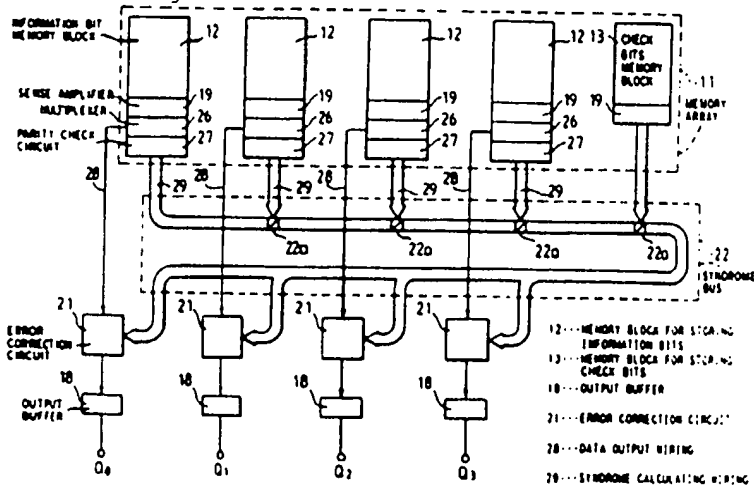
Abstract (Basic): US 5056095 A

The semiconductor memory comprises a set of memory blocks (12) for storing information bits, another memory block (13) for storing test bits, set of multiplexers (26) disposed at the respective output sections of the memory blocks (12), a set of parity test circuits (26) each responding to bit information for a parity test which is generated from one output from the corresponding one of the multiplexers (26).

A syndrome bus (22) responds to both the respective outputs of the parity test circuits (26) and the output of the another memory block (13), and a set of error correction circuits (31) each respond to both output data (28) generated from the other output of the corresponding one of the multiplexers (26) and a syndrome generated from the syndrome bus (22).

ADVANTAGE - Reduces number of wirings between memory blocks and error correction circuits, reduces chip area.

Dwg.1/6



Title Terms: SEMICONDUCTOR; MEMORY; ERROR; CORRECT; CIRCUIT; **MULTIPLEX** ;
OUTPUT; MEMORY; BLOCK; HOLD; INFORMATION; TEST; BIT; PARITY; TEST;
CIRCUIT; RESPOND; **MULTIPLEX**

Derwent Class: U14; U21

International Patent Class (Main): G11C-011/34

International Patent Class (Additional): H03M-013/00

File Segment: EPI

Manual Codes (EPI/S-X): U14-D02; U21-A06

DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

008404651 **Image available**

WPI Acc No: 1990-291652/199039

Related WPI Acc No: 1989-017004; 1992-058420; 1992-301762; 1997-300624;
1998-002152

XRPX Acc No: N90-224538

**Cell switching system for time division multiplexers - using common
cell memory buffer and cell address storage to detect write and chain
breaking errors**

Patent Assignee: HITACHI LTD (HITA); HITACHI KK (HITA); GOHARA S
(GOHA-I); HORIKI A (HORI-I); KATO T (KATO-I); KUWAHARA H (KUWA-I); MORI M
(MORI-I); OHTSUKI K (OHTS-I); SAKURAI Y (SAKU-I); AIKI K (AIKI-I); AOKI K
(AOKI-I); ITO Y (ITOY-I); KOZAKI T (KOZA-I); YANAGI J (YANA-I)

Inventor: GOHARA S; KOZAKI T; SAKURAI Y; HORIKI A; KATO T; KUWAHARA H; MORI
M; OHTSUKI K; AIKI K; AOKI K; ITO Y; YANAGI J

Number of Countries: 005 Number of Patents: 020

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
EP 388648	A	19900926	EP 90103343	A	19900221	199039 B
JP 2220532	A	19900903	JP 8940230	A	19890222	199041
US 5124977	A	19920623	US 90482090	A	19900220	199228
EP 388648	A3	19920122	EP 90103343	A	19900221	199322
EP 388648	B1	19970122	EP 90103343	A	19900221	199709
DE 69029755	E	19970306	DE 629755	A	19900221	199715
			EP 90103343	A	19900221	
US 5710770	A	19980120	US 88218217	A	19880713	199810
			US 90482090	A	19900220	
			US 91745466	A	19910814	
			US 92845668	A	19920304	
			US 94306978	A	19940916	
			US 95462532	A	19950605	
US 5799014	A	19980825	US 90482090	A	19900220	199841
			US 91745466	A	19910814	
			US 92845668	A	19920304	
			US 94306978	A	19940916	
US 6016317	A	20000118	US 88218217	A	19880713	200011
			US 90482090	A	19900220	
			US 91745466	A	19910814	
			US 92845668	A	19920304	
			US 94306978	A	19940916	
			US 95462269	A	19950605	
US 36716	E	20000530	US 88218217	A	19880713	200033
			US 90482090	A	19900220	
			US 95430809	A	19950426	
US 36751	E	20000627	US 88218217	A	19880719	200036
			US 90482090	A	19900220	
			US 91745466	A	19910814	
			US 92845668	A	19920304	
			US 95430802	A	19950426	
US 6215788	B1	20010410	US 88218217	A	19880713	200122
			US 90482090	A	19900220	
			US 92845668	A	19920304	
			US 94306978	A	19940916	
			US 95462269	A	19950605	
			US 99292985	A	19990416	
US 20010005386	A1	20010628	US 88218217	A	19880713	200138
			US 90482090	A	19900220	
			US 92845668	A	19920304	
			US 94306978	A	19940916	
			US 95430802	A	19950426	
			US 95430809	A	19950426	
			US 95462269	A	19950605	
			US 99292985	A	19990416	
			US 2000725241	A	20001129	
US 6285675	B1	20010904	US 88218217	A	19880713	200154
			US 90482090	A	19900220	

			Cont of application US 92845668
			Cont of application US 94306978
			Cont of application US 95462532
			CIP of patent US 4910731
			Cont of patent US 5124977
			Cont of patent US 5365519
			Cont of patent US 5710770
			Cont of patent US 5799014
US 6339596	B1	H04L-012/56	CIP of application US 88218217
			CIP of application US 90482090
			Cont of application US 92845668
			Cont of application US 94306978
			CIP of patent US 4910731
			CIP of patent US 5124977
			Cont of patent US 5365519
			Cont of patent US 5799014
US 6396831	B1	H04L-012/56	CIP of application US 88218217
			CIP of application US 90482090
			Cont of application US 92845668
			Cont of application US 94306978
			Cont of application US 95462532
			Cont of application US 97925050
			CIP of patent US 4910731
			CIP of patent US 5124977
			Cont of patent US 5365519
			Cont of patent US 5710770
			Cont of patent US 5799014
US 6445703	B2	H04L-012/56	CIP of application US 88218217
			CIP of application US 90482090
			Cont of application US 92845668
			Cont of application US 94306978
			Cont of application US 95462269
			Cont of application US 99292985
			CIP of patent US 4910731
			CIP of patent US 5124977
			Cont of patent US 5365519
			Cont of patent US 5799014
			Cont of patent US 6016317
US 6546011	B1	H04L-012/56	CIP of application US 88218217
			CIP of application US 90482090
			Cont of application US 92845668
			Cont of application US 94306978
			Cont of application US 95462269
			Cont of application US 99228748
			CIP of patent US 4910731
			CIP of patent US 5124977
			Cont of patent US 5365519
			Cont of patent US 5799014
			Cont of patent US 6016317
			Cont of patent US 6285675

Abstract (Basic): EP 388648 A

A switching system handles a numbers of communication cells, each of which has a header section deifning its destination and also a data section. Cells arrive over incoming highways (1) and are transmitted on outgoing highways (6) in accordance with the cell header information.

The cells are held in a common buffer memory (5) while a **second memory** (4) **stores** the addresses of empty cells. Read and wi)write operations of the common memory are controlled (3) by the empty address memory. **Errors** are **detected** by a number of units (20, 22, 24-27, 30-34).

USE/ADVANTAGE - Provides **detection** of **errors** promptly and hence a rapid re-initialisation of the system.

Dwg.1/17

Abstract (Equivalent): EP 388648 B

A switching system for handling a plurality of cells, each cell including a header section and a data section, and for exchanging a communication message contained in the data section of the cell between

a plurality of incoming highways (1N) and a plurality of outgoing highways (OUT) according to the data contained in the header section of the cell, comprising: means (1) for **multiplexing** said incoming highways (1N) in time division; first memory means (5) having addressable storage locations for storing cells received from said **multiplexing** means (1); means (6) for demultiplexing and distributing data output from said first memory means (5) among said plurality of outgoing highways (OUT); **second memory** means (4) for storing an empty address of an empty storage location of the first memory means (5); and means (3) for controlling the write and read operations of said first memory means in accordance with an empty address stored in the **second memory** means used as write and read addresses; characterised by further comprising means (20,22,24-27,30-34) for **detecting an error** in at least one of the write address and read address and producing an error signal.

Dwg.1/17

Abstract (Equivalent): US 5710770 A

The system has a switch unit (1) including input ports and output ports having the same cell transmission rate. A **multiplexer** (12) **multiplexes** cell trains outputted from output ports into a single cell train, and outputs the train to a high-speed output line (and/or demultiplexer for outputting cell trains to low-speed output lines). The switch unit includes a buffer memory (11) for temporarily storing cells inputted while forming a queue chain for each line to which each cell is to be outputted.

A demultiplexer (13) distributes the cells read from the buffer memory among the output ports in circulation. A circuit (10) controls the write and read operation of cells with the buffer memory, using a control table device.

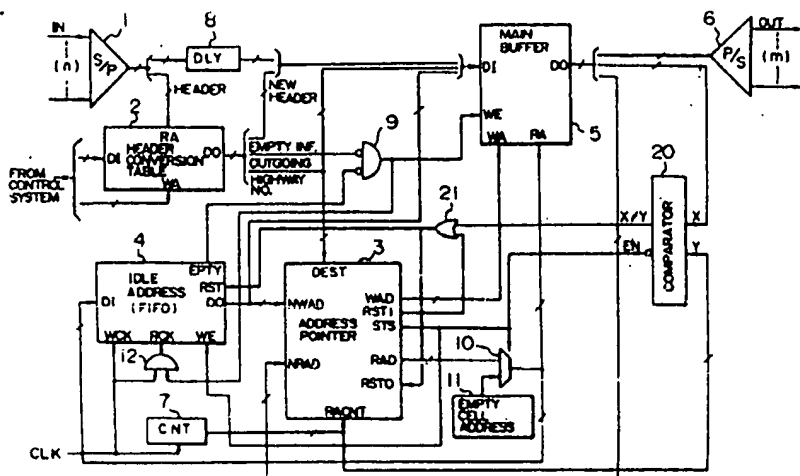
ADVANTAGE - Cell switching operation is in accordance with cell transmission rate of output line to be accommodated. Output lines can be of different transmission rates, e.g. 600 Mbps. 150 Mbps and 50 Mbps.

Dwg.2/11

US 5124977 A

The switching system handles a number of cells, each including a header section and a data section, and exchanges a communication message contained in the data section of the cell between a number of incoming highways and a number of outgoing highways according to the data contained in the header section of the cell. The switching system includes a unit for **multiplexing** the incoming highways in time division, a first memory having addressable storage locations for storing cells received from the **multiplexing** unit. A unit demultiplexes and distributes data output from the first memory among a number of outgoing highways. A **second memory stores** an empty address of an empty storage location of the first memory. A unit controls the write and read operations of the first memory in accordance with an empty address stored in the **second memory** used as write and read addresses. An **error is detected** in a least one of the write address and read address. ADVANTAGE - Automatically **detects error** in write or read address for main buffer.

(Dwg.1/17



Title Terms: CELL; SWITCH; SYSTEM; TIME; DIVIDE; **MULTIPLEX** ; COMMON; CELL; MEMORY; BUFFER; CELL; ADDRESS; STORAGE; DETECT; WRITING; CHAIN; BREAK; ERROR

Derwent Class: W01; W02

International Patent Class (Main): H04L-012/28; H04L-012/56; H04Q-011/00; H04Q-011/04

International Patent Class (Additional): H04J-003/02; H04L-012/50

File Segment: EPI

Manual Codes (EPI/S-X): W01-A03A2; W01-A06X; W01-A07; W02-K09

7/19/18 (Item 18 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

007851208 **Image available**

WPI Acc No: 1989-116320/198916

Control circuit for FIFO memory - has storage registers to temporarily store output from counters for reloading if error occurs

Patent Assignee: NORTHERN TELECOM LTD (NELE)

Inventor: CIANCIBELLO C A; GEADAH Y A; LEFEBVRE M C; CIANCIBELL C A

Number of Countries: 009 Number of Patents: 006

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
EP 312239	A	19890419	EP 88309253	A	19881005	198916 B
US 4873666	A	19891010	US 87108655	A	19871015	198950
CN 1035382	A	19890906				199028
CA 1286421	C	19910716				199133
EP 312239	B1	19960508	EP 88309253	A	19881005	199623
DE 3855274	G	19960613	DE 3855274	A	19881005	199629
			EP 88309253	A	19881005	

Priority Applications (No Type Date): CA 549274 A 19871014; US 87108655 A 19871015

Cited Patents: A3...9107; No-SR.Pub; US 4616338; WO 8400835

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
EP 312239	A	E	14		

Designated States (Regional): DE FR GB IT NL SE

US 4873666	A	11
------------	---	----

EP 312239	B1	E	13	G06F-005/06
-----------	----	---	----	-------------

Designated States (Regional): DE FR GB IT NL SE

DE 3855274	G		G06F-005/06	Based on patent EP 312239
------------	---	--	-------------	---------------------------

Abstract (Basic): EP 312239 A

A write counter (217) and a read counter (218) are clocked by a clock signal (A). The output of the write counter including the overflow bit is applied to a **multiplexer** (219) register (243) and comparator (251). The output of the read counter is applied to the other input (A) of the **multiplexer** , to a further register (244) and

to a further comparator (241) of which the other input comes from the output of the write counter register (243).

The comparator operate for indicating the full condition or the empty condition of the memory. The storage registers (243, 244) are able to reload the respective write counter, read counter if an error, such as a **parity errors**, is **detected** on the message.

ADVANTAGE - No up-down counter, with its attendant complexity, is required. Re-writing and re-reading section of memory can be achieved. (14pp Dwg.No.3/4

Abstract (Equivalent): EP 312239 B

A control circuit for a FIFO (first in first out) memory circuit for providing address information (224) to a FIFO memory means (212) having an address field of n bits, the control circuit comprising means (217, 243) for generating a write address signal, means (218, 244) for generating a read address signal, and means (219) for selecting one or other of the write address signal and the read address signal as the address information for the FIFO memory means, characterised by: the write address and the read address signals having $n + 1$ bits of which the n least significant bits are output by the means (219) for selecting as the address information for the FIFO memory means; a first comparator (248) for comparing the most significant bit of the write address signal with the most significant bit of the read address signal whereby to generate a first comparison signal (249) indicative of equality or non-equality of said most significant bits; a second comparator (251) for comparing the n least significant bits of the write address signal with the n least significant bits of the read address signal whereby to generate a second comparison signal (252) indicative of equality or non-equality of said least significant bits; and logic means (253) responsive to the first comparison signal indicating non-equality and the second comparison signal indicating equality, for generating a signal (247) indicative of the memory means being full.

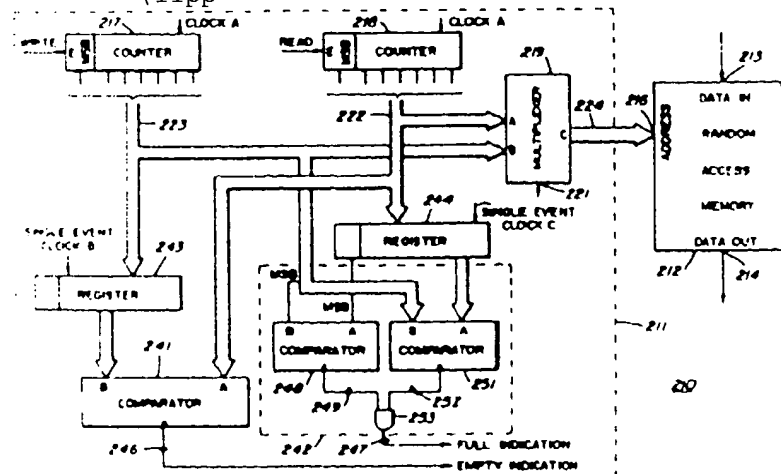
(Dwg.3/4)

Abstract (Equivalent): US 4873666 A

A FIFO (first in first out) control circuit for providing address information to a FIFO memory uses two up counters one to provide the write address and one to provide the read address. A **multiplexer** selects which address (read or write) are used. **Two storage registers** are used to temporarily "hold" the output from the counters. This enables the counters to be re-loaded with their original "count" to enable either a re-reading or a re-writing of a message stored in the FIFO memory.

Comparators and logic circuitry are used to provide two status output signals, namely full (or not) and empty (or not).

(11pp



Title Terms: CONTROL; CIRCUIT; FIFO; MEMORY; STORAGE; REGISTER; TEMPORARY; STORAGE; OUTPUT; COUNTER; RELOAD; ERROR; OCCUR
Derwent Class: T01
International Patent Class (Main): G06F-005/06
International Patent Class (Additional): G11C-005/00; G11C-007/00;

G11C-008/00
File Segment: EPI
Manual Codes (EPI/S-X): T01-D; T01-H01D

7/19/19 (Item 19 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

007565278 **Image available**
WPI Acc No: 1988-199210/198829
XRPX Acc No: N88-152023

Diagnosing and testing performance of interface module - connecting PCM transmission path of digital TDM telephone exchange to exchange with voice memory

Patent Assignee: SIEMENS AG (SIEI)
Inventor: JUGEL A; MARTIN H; STEIS B; STTEIS B
Number of Countries: 013 Number of Patents: 007
Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
EP 274653	A	19880720	EP 87117979	A	19871204	198829 B
BR 8706853	A	19880726				198835
FI 8705541	A	19880618				198842
EP 274653	B	19910807				199132
DE 3772024	G	19910912				199138
FI 88984	B	19930415	FI 875541	A	19871216	199320
DK 167792	B	19931213	DK 876611	A	19871216	199404

Priority Applications (No Type Date): DE 3643099 A 19861217
Cited Patents: 2.Jnl.Ref; A3...8831; No-SR.Pub
Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
EP 274653	A	G	7		
Designated States (Regional): AT BE CH DE FR GB IT LI NL SE					
EP 274653	B				
Designated States (Regional): AT BE CH DE FR GB IT LI NL SE					
FI 88984	B			H04M-003/24	patent FI 8705541
DK 167792	B			H04M-003/24	patent DK 8706611

Abstract (Basic): EP 274653 A

Test circuits including their following fault counters, voice memory (SM), and the computer interface (DB/CR) are subjected to routine tests during the unchanged continuing correct operation of the interface module (FAV). The test circuits receive signals simulating faults.

When a test circuit responds as though in the presence of a real fault, the fault in that function is recorded in a state register (SR) and the fault counter is moved on but none of the events that would occur in the presence of a real fault are initiated.

2/2

Abstract (Equivalent): EP 274653 B

Method for diagnosing and testing an interface unit for connecting a PCM transmission link of a digital time-division **multiplex** telecommunication system to an exchange in a telecommunication system, which, in addition to **other** components, exhibits a speech **memory** for adapting the timing of the pulse frame formed on the transmission link to the pulse frame on which the operation of the exchange is based, which itself is furthermore equipped with a number of monitoring circuits evaluating different criteria of the information transmission on the PCM link, which are at least partially associated with error counters, and which is connected to a separate control system via a computer interface, characterised in that the test circuits (U-AIS, U-NOS, U-DCV, U-CRC4, U-SM) and subsequent error counters, the speech memory (SM) and the computer interface (DB/CR) are subjected to routine tests during the proper operation of the interface unit (FAU) which continues unchanged, for which purpose, apart from the criteria to be monitored by them, simulation quantities corresponding to an error are applied to the test circuits under control by the control system, in

[illegible]

Manual Codes (EPI/S-X): W01-B07; W01-C02A1

(c) 2003 Thomson Derwent. All rts. reserv.

XRPX Acc No: N87-244406

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week	
SU 1302329	A	19870407	SU 4004952	A	19851230	198746	B

SU 1302329 A 5

USE/ADVANTAGE - In computing technique for a self-monitoring memory

to **detect** unidirectional **errors** in **two memory** modules and to correct unidirectional errors in one memory module, monitoring is more certain and information capacity is increased. The number of word digits is doubled. The ordinal numbers of failed memory modules are encoded. Bul.13/7.4.87 (5pp Dwg.No.1/5)

Title Terms: COMPUTATION; SELF; MONITOR; MODULE; MEMORY; CODE; TWO; ERROR; LOCATE; COMPARE; FORM; OUTPUT; SIGNAL; THROUGH; OR-GATE; SIGNAL; CORRECT; ERROR; ONE; MODULE

Derwent Class: U14

International Patent Class (Additional): G11C-029/00

File Segment: EPI

Manual Codes (EPI/S-X): U14-D02

7/19/21 (Item 21 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

007329871

WPI Acc No: 1987-326878/198746

XRPX Acc No: N87-244404

Computing modular error correcting memory - has two error detectors each forming module ordinal number when two modules fail

Patent Assignee: MOSC POWER INST (MOPO)

Inventor: BORODIN G A

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
SU 1302327	A	19870407	SU 3997905	A	19851230	198746 B

Priority Applications (No Type Date): SU 3997905 A 19851230

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
SU 1302327	A	6		

Abstract (Basic): SU 1302327 A

The circuitry contg. **two** control digit forming circuits for **memory** modules with outputs to another two control digit forming circuits, an error corrector, two comparators, **multiplexer** and an **error detector**, has the control digit forming circuits (18,19). Berger code forming circuits, two more comparators, another **error detector** and a type of error finder.

USE/ADVANTAGE - In computing as memory with self-monitoring by **detection** of modular unidirectional **errors** in **two memory** modules and their correction in one, monitoring is more certain. The presence of the two errors is determined by comparison. The codes of the ordinal numbers of the failed modules are formed by two detectors. The third detector forms a signal for correction and an incorrecible error signal. Bul.13/7.4.87 (6pp Dwg.No.1/6)

Title Terms: COMPUTATION; MODULE; ERROR; CORRECT; MEMORY; TWO; ERROR; DETECT; FORMING; MODULE; ORDINAL; NUMBER; TWO; MODULE; FAIL

Derwent Class: U14

International Patent Class (Additional): G11C-029/00

File Segment: EPI

Manual Codes (EPI/S-X): U14-D02

7/19/22 (Item 22 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

007085616

WPI Acc No: 1987-085613/198712

XRPX Acc No: N87-064280

Memory units tester - uses arithmetic unit to form current data for input to multiplexer via register

Patent Assignee: KIEV ELTRN COMPUTER (KIEL-R)

Inventor: BELALOV F Y A; BOCHKOV V K; PUDAKOV E V

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
SU 1247951	A	19860730	SU 3878097	A	19850226	198712 B

Priority Applications (No Type Date): SU 3878097 A 19850226

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
SU 1247951	A	6		

Abstract (Basic): SU 1247951 A

The appts. includes control unit (2) arithmetic unit (1) two comparators (6,7) and six registers (17-22). For faster response it is further equipped with accumulators (3-5) **multiplexers** (10-16) further registers (23-30), counter (31), decoder (8) signals shaper (9), **parity tester** (32), two switches (33,34) and indicators (35-37).

The arithmetic unit (1) analyses initial parameters which are received through the registers (26-30) through the **multiplexer** (12) and a current access address to a tested unit is formed. Results of operation of the arithmetic unit (1) and the **other** data are stored in the **memory** of said unit. A current address from the arithmetic unit is transferred to the register (19) the **multiplexer** (14) and through the **multiplexer** (15) to the register (20) the comparator (7) compares the present (current) address with the final address.

USE - In computer engineering for tuning and testing operational and peripheral memories. Bul. 28/30.7.86

Dwg.1/2

Title Terms: MEMORY; UNIT; TEST; ARITHMETIC; UNIT; FORM; CURRENT; DATA; INPUT; **MULTIPLEX** ; REGISTER

Derwent Class: U14

International Patent Class (Additional): G11C-029/00

File Segment: EPI

Manual Codes (EPI/S-X): U14-D03

7/19/23 (Item 23 from file: 350)

DIALOG(R)File 350:Derwent WPIX

(c) 2003 Thomson Derwent. All rts. reserv.

003352140

WPI Acc No: 1982-L0162E/198233

Memory with self checking facility - has control signals former comparator and multiplexer coupled to register

Patent Assignee: MOSC POWER INST (MOPO)

Inventor: BORODIN G A; EGOROVA N I; OGNEV I V

Number of Countries: 001 Number of Patents: 001

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
SU 875456	B	19811023				198233 B

Priority Applications (No Type Date): SU 2883225 A 19800214

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
SU 875456	B	5		

Abstract (Basic): SU 875456 B

Memory with self-checking facility uses a **second store** , control signals former, comparator and multiplier to increase effective capacity. Binary codes are applied directly to the first store (1) with checking codes stored in the first group parity signal formers (3,4). Checking digits are formed by adding weighting marks to the formers' code.

During read-out, the store (1) data are transferred to the output register (6) and the second group parity signals former (7). Parity codes are compared for **detecting storage errors** . Faulty cell address is discriminated by using a **second comparator** (10) and **store** (2). Permanent **second store** accumulates both comparators' (9,10) results, storing the faulty cells address code. Error correction is

effected through the **multiplexer** (5) and the numbers register (6).
Bul. 39/23.10.81. (5pp Dwg.No.1/1)
Title Terms: MEMORY; SELF; CHECK; FACILITY; CONTROL; SIGNAL; FORMER;
COMPARATOR; **MULTIPLEX** ; COUPLE; REGISTER
Derwent Class: T01; U14
International Patent Class (Additional): G11C-011/00
File Segment: EPI
Manual Codes (EPI/S-X): T01-H; U14-A20; U14-D

7/19/24 (Item 24 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

002353372
WPI Acc No: 1980-F9821C/198028
Error detection in microprocessor systems - by executing error
routine during access period of macro-programmed memory
Patent Assignee: STAND ELEK LOREN (INTT)
Inventor: ILLI D
Number of Countries: 001 Number of Patents: 001
Patent Family:
Patent No Kind Date Applicat No Kind Date Week
DE 2855004 A 19800703 198028 B

Priority Applications (No Type Date): DE 2855004 A 19781220

Abstract (Basic): DE 2855004 A

An **error detector** routine for microprocessor systems operates during the accessing period required for macro-instructions and so does not slow down the operation of the system.

The central processor is controlled by a micro programme store for executing all internal control signal generations. User data is entered from a **separate memory** over a register and **multiplexer**. Macro-instructions, such as jump operations, are held in a programme store coupled over a register and first-in-first out memory. During the access period of the macro store, an **error checking** operation is performed. Test data held in a register is delivered and transmitted to mask register. The generated data is **multiplexed** into a second register and is compared with the output to indicate any error.

Title Terms: ERROR; DETECT; MICROPROCESSOR; SYSTEM; EXECUTE; ERROR; ROUTINE
; ACCESS; PERIOD; MACRO; PROGRAM; MEMORY
Derwent Class: T01
International Patent Class (Additional): G06F-011/00
File Segment: EPI
Manual Codes (EPI/S-X): T01-G02

7/19/25 (Item 25 from file: 350)
DIALOG(R)File 350:Derwent WPIX
(c) 2003 Thomson Derwent. All rts. reserv.

002310462
WPI Acc No: 1980-B6893C/198008
Checking system for integrated storage matrix - divides latter into two
independently addressed zones with some words used as check words
Patent Assignee: SIEMENS AG (SIEI)
Inventor: ELSNER P
Number of Countries: 001 Number of Patents: 001
Patent Family:
Patent No Kind Date Applicat No Kind Date Week
DE 2834745 A 19800214 198008 B

Priority Applications (No Type Date): DE 2834745 A 19780808

Abstract (Basic): DE 2834745 A

The checking system uses an auxiliary store (HS) for listing the addresses of storage cells where an **error** is **detected**. The store is

divided into two equal, independently addressed zones (SB1, SB2), with words read from one zone used as checks words for the words read from the storage cells of the other zone.

A checking counter (Zp) provides the addresses of the check words, with two **multiplexers** (MPX1, MPX2) for independently addressing the **two storage** zones (SB1, SB2) with the check word and an externally demanded storage word supplied to a device (F) for error recognition and correction.

Title Terms: CHECK; SYSTEM; INTEGRATE; STORAGE; MATRIX; DIVIDE; LATTER; TWO ; INDEPENDENT; ADDRESS; ZONE; WORD; CHECK; WORD

Derwent Class: U14

International Patent Class (Additional): G11C-029/00

File Segment: EPI

7/19/26 (Item 26 from file: 347)

DIALOG(R) File 347:JAPIO

(c) 2003 JPO & JAPIO. All rts. reserv.

06097713 **Image available**

MEMORY MONITORING CIRCUIT

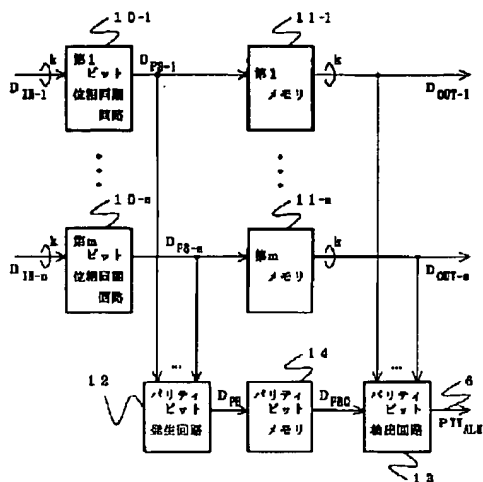
PUB. NO.: 11-039232 [JP 11039232 A]
PUBLISHED: February 12, 1999 (19990212)
INVENTOR(s): HASEGAWA TOMOHIKO
APPLICANT(s): NEC ENG LTD
APPL. NO.: 09-196725 [JP 97196725]
FILED: July 23, 1997 (19970723)
INTL CLASS: G06F-012/16; G06F-012/16

ABSTRACT

PROBLEM TO BE SOLVED: To make a memory versatile and, at the same time, to simplify a constitution for monitoring the memory.

SOLUTION: Bit phase synchronizing circuits 10-1 to 10-m which respectively output the input signals to all memories 11-1 to 11-m which write (k) input signals **multiplexed** with and synchronized to N words by synchronizing the bit phases of the signals to each **other** to the **memories** 11-1 to 11-m are provided on the input sides of the memories 11-1 to 11-m. One set of circuits composed of a parity bit generating circuit 12 which generates one parity bit signal DPB by connecting the outputs of the circuits 10-1 to 10-m and adding one vertical parity to received data and stores the data DPB in a parity bit memory 14 and a **parity** bit **detecting** circuit 13 which generates a parity bit output data signal DPB by connecting the outputs of the memories 11-1 to 11-m and adding one vertical parity to all data and compares the signal DPBO with the previously stored data signal DPB can monitor the parities of the memories 11-1 to 11-m each of which does not require any larger capacity than the (k) input signals.

COPYRIGHT: (C)1999, JPO



7/19/28 (Item 28 from file: 347)
 DIALOG(R) File 347:JAPIO
 (c) 2003 JPO & JAPIO. All rts. reserv.

02955452 **Image available**
 MONITORING SYSTEM FOR MEMORY

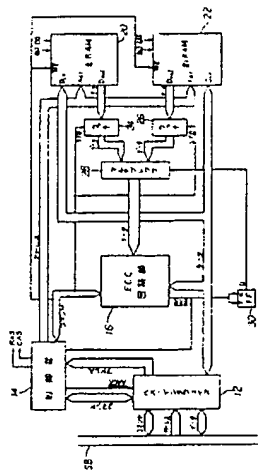
PUB. NO.: 01-253052 [JP 1253052 A]
 PUBLISHED: October 09, 1989 (19891009)
 INVENTOR(s): YOSHII TOSHIHARU
 APPLICANT(s): NEC CORP [000423] (A Japanese Company or Corporation), JP
 (Japan)
 APPL. NO.: 63-080480 [JP 8880480]
 FILED: April 01, 1988 (19880401)
 INTL CLASS: [4] G06F-012/16
 JAPIO CLASS: 45.2 (INFORMATION PROCESSING -- Memory Units)
 JOURNAL: Section: P, Section No. 984, Vol. 13, No. 590, Pg. 165,
 December 26, 1989 (19891226)

ABSTRACT

PURPOSE: To securely **detect** even a fixed **error** by writing and reading a time- division **multiplex** signal (TDM) by using 1st and 2nd **memories** alternately, and writing and reading test pattern data (TPD) by using a 3rd memory and checking the read TPD.

CONSTITUTION: A memory for time slot conversion is provided with the 1st-3rd memories 11a-11c, the 1st and 2nd **memories** 11a and 11b are used to write and read the TDM, and the 3rd memory 11c is used to write and read the TPD and also check the read TPD. Then those are written and read by being shifted to the 1st-3rd memories 11a-11c in order repeatedly. Consequently, the respective memories can be monitored by turns and the RAMs 11a-11c are reduced in necessary capacity and a failure in **error detection** due to readout fixation to a normal state is eliminated.

CONSTITUTION: The same data is stored in both a main ROM 20 and a **secondary RAM 22** together with an **error detection** code used for correction of an error. A **multiplexer 28** selects the data received from the RAM 20 or the RAM 22 and outputs it to an ECC circuit part 16. Thus the circuit 16 **detects** the **error** of the data selected by the **multiplexer 28**. When the number of error bits is small and the part 16 itself can correct the error, the correction data are written again to the RAM 20 and the RAM 22. While the data selected by the **multiplexer 28** are changed if the number of error bits is large.



7/19/30 (Item 30 from file: 347)
 DIALOG(R)File 347:JAPIO
 (c) 2003 JPO & JAPIO. All rts. reserv.

01985004 **Image available**
 MEMORY **MULTIPLEXING** CONTROL SYSTEM

PUB. NO.: 61-199104 [JP 61199104 A]
 PUBLISHED: September 03, 1986 (19860903)
 INVENTOR(s): OKAMOTO TADASHI
 AZUSAWA NOBORU
 YAMAOKA HIROMASA
 APPLICANT(s): HITACHI LTD [000510] (A Japanese Company or Corporation), JP
 (Japan)
 APPL. NO.: 60-038772 [JP 8538772]
 FILED: March 01, 1985 (19850301)
 INTL CLASS: [4] G05B-009/03
 JAPIO CLASS: 22.3 (MACHINERY -- Control & Regulation)
 JAPIO KEYWORD: R129 (ELECTRONIC MATERIALS -- Super High Density Integrated
 Circuits, LSI & GS; R131 (INFORMATION PROCESSING --
 Microcomputers & Microprocessors)
 JOURNAL: Section: P, Section No. 540, Vol. 11, No. 29, Pg. 37, January
 28, 1987 (19870128)

ABSTRACT

PURPOSE: To realize **multiplexing** easily without damaging the economization by cascading plural memory devices and writing and reading the same data in and from the same addresses of all memory devices at the same timing.

CONSTITUTION: **Error checkers** 13, memory **multiplexing** control circuits 14, and **multiplexing** control signals 6-1-6-(n-1) cascading adjacent memory devices are provided, and the same data is written or read in and from the same addresses of all memory devices 4-1-4-n at the same timing, and data is written or read in or from the first memory device if the first memory device is normal; but if data **error** is **detected**, the abnormality of the first memory device is reported to the **second memory** device by a **multiplexing** signal to write or read data in or from the **second memory**; and if the first - the (i-1)th memory devices are abnormal, data is written in or read from the i-th memory device. Thus, the memory **multiplexing** operation is performed.

